

<b>Notice of References Cited</b>	Applicant/Patent <b>Li et al.</b>	Application/Control No. <b>09/513,207</b>	
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\* A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

<sup>1</sup> Dates in MM-YYYY format are publication dates.

<sup>2</sup> Classifications may be U.S. or foreign.

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